Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination		
10/699,117	PARK ET AL.		
Examiner	Art Unit		
Tae H. Yoon	1714		

SEARCHED					
Class	Subclass	Date	Examiner		
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INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	

SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
	DATE	EXMR	
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